



Interference Searched 	Application/Control No. 08908453	Applicant(s)/Patent Under Reexamination RUVKUN ET AL.
	Examiner Paras, Jr., Peter	Art Unit 1632


Class	Sub Class	Date	Examiner
536	23.5	2/21/2006	Paras
435	194, 320.1, 325, 6, 7.1, 70.1	2/21/2006	Paras

U.S. Patent and Trademark Office	Part of Paper No.:	2202006
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	<p>Examiner</p> <p>Paras, Jr., Peter</p>	<p>Art Unit</p> <p>1632</p>

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updated; STIC sequence search: SEQ ID NOs: 1, 2; appeal/patentability conference with Ram Shukla and Dave Nguyen; Inventor Name Search; 60/023,382	2/21/2006	Paras <i>PS</i>
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